

# Notes on Diffusion Data in the Cu-In-Se System for Application in CIS photovoltaic cells

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# Binaries in the Cu-In-Se System

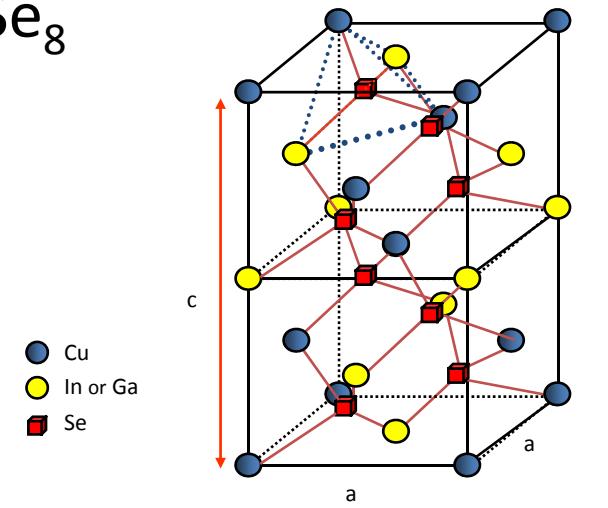
- Cu-In binary system
  - 3 solution phases: liquid, fcc(Cu) and  $\beta$  (bcc)
  - 2 ordered phases:  $\gamma$  and  $\eta'$
  - 3 stoichiometric phases:  $\delta$  ( $\text{Cu}_{0.7}\text{In}_{0.3}$ ),  $\eta$  ( $\text{Cu}_{0.64}\text{In}_{0.36}$ ) and  $\text{Cu}_{11}\text{In}_9$
- In-Se
  - 2 solution phases (Se and In)
  - 1 ionic liquid
  - 6 stoichiometric phases ( $\text{In}_4\text{Se}_3$ ,  $\text{InSe}$ ,  $\text{In}_6\text{Se}_7$ ,  $\text{In}_9\text{Se}_{11}$ ,  $\text{In}_5\text{Se}_7$  and the polymorphic  $\text{In}_2\text{Se}_3$  ( $\alpha, \beta, \gamma$ , and  $\delta$ ))
- Cu-Se
  - 2 solution phases fcc(Cu) and Se
  - 1 ionic liquid
  - 3 stoichiometric compounds:  $\text{Cu}_{2-x}\text{Se}$ ,  $\text{Cu}_3\text{Se}_2$ ,  $\text{CuSe}$  and  $\text{CuSe}_2$ 
    - $\text{Cu}_{2-x}\text{Se}$  has 2 polymorphs ( $\alpha$  and  $\beta$ )
    - $\text{CuSe}$  has 3 polymorphs  $\alpha$ -CuSe,  $\beta$ -CuSe and  $\gamma$ -CuSe
  - 1 ordered phase  $\text{Cu}_{2-x}\text{Se}$  which has 2 polymorphs ( $\alpha$  and  $\beta$ )
    - 3 sublattice model ( $\text{Cu}, \text{Va}1(\text{Se})1(\text{Cu})1$ )



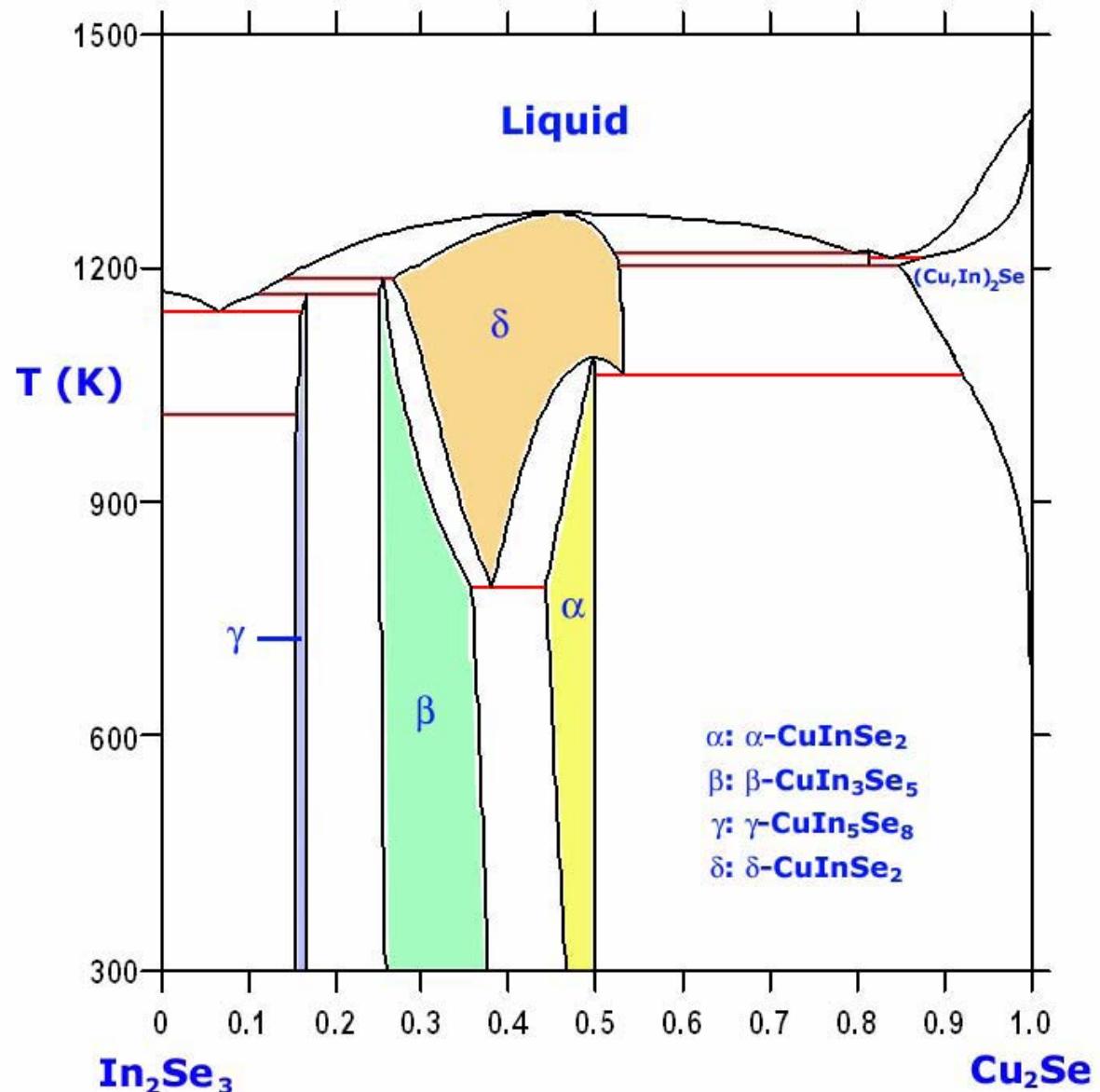
# Ternary Cu-In-Se

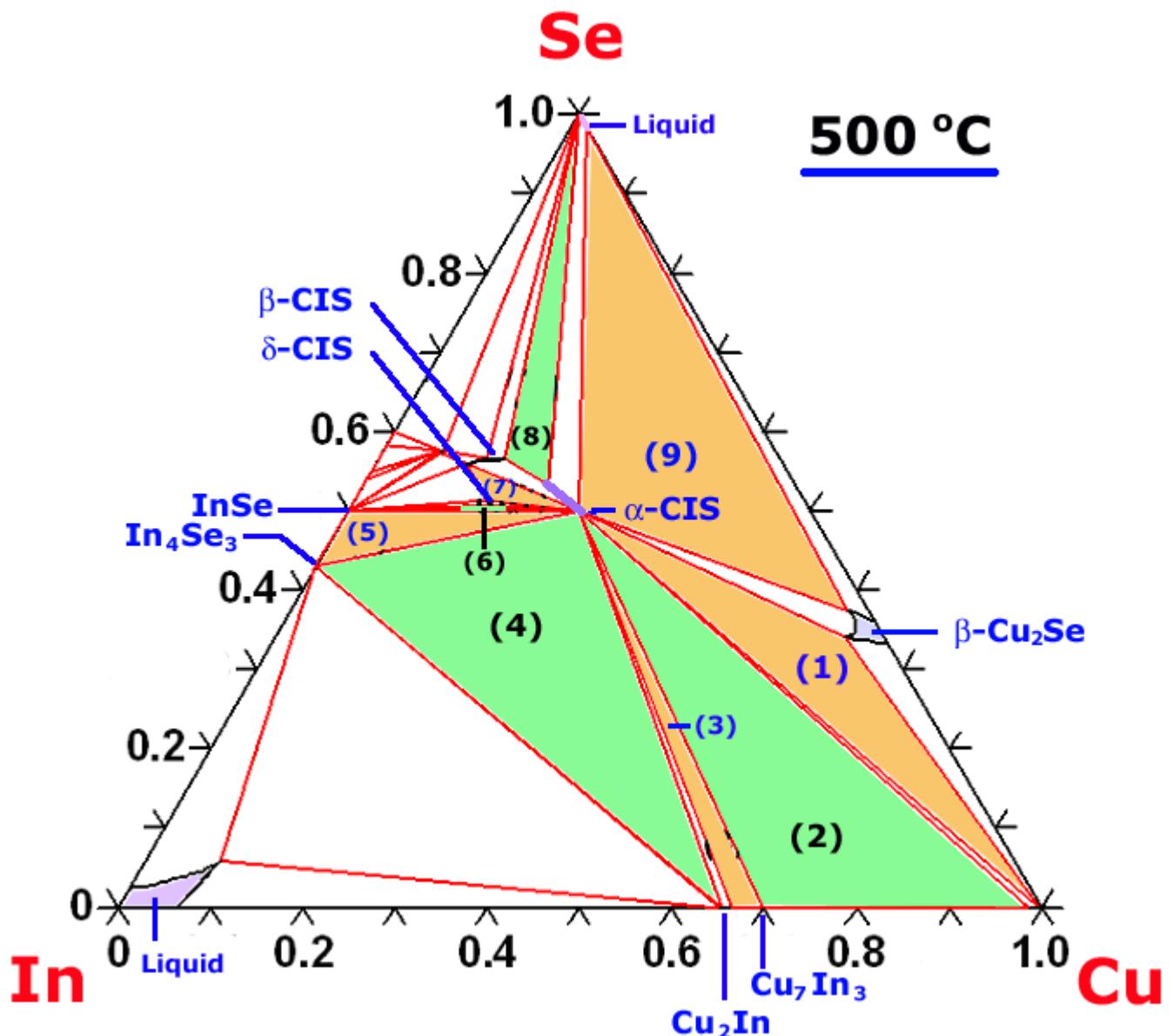
- 1 Ionic Liquid (Cu+1, In+3) (Se-2, Va, Se)
- $\alpha \text{ CuInSe}_2 (\text{Cu}\%, \text{In}, \text{Va})(\text{Cu}, \text{In}\%, \text{Va})\text{Se}_2$  (Chalcopyrite)
- $\delta \text{ CuInSe}_2 (\text{Cu}\%, \text{In}, \text{Va})_2 \text{Se} (\text{Se}, \text{Va})_2$  (Sphalerite)
- $\beta \text{ CuIn}_3\text{Se}_5 (\text{Cu}\%, \text{In}, \text{Va}) (\text{Cu}, \text{In}, \text{Va})_3\text{Se}_5$  (Defect Chalcopyrite)
- $\gamma \text{ CuIn}_5\text{Se}_8 (\text{Cu}\%, \text{In}, \text{Va}) (\text{Cu}, \text{In}\%, \text{Va})_5 \text{Se}_8$
- $\text{Cu}_2\text{In} (\text{Cu}, \text{In})_2(\text{Cu}, \text{In})(\text{Se}, \text{Va})$
- $\beta \text{ Cu}_2\text{Se} (\text{Cu}, \text{Va}) \text{Se} (\text{Cu}, \text{In})$

Assume  $\alpha$ -CuInSe<sub>2</sub> is composed of a cubic cation sublattice and a cubic anion sublattice.



Chalcopyrite CIGS structure





# Processing of $\alpha$ -CuInSe

- Co-Deposition of elements
- Annealing of stacked elemental layers
- Direct compound formation
- Selenization of metal particles

# Reactions during Thermal Processing

- $\text{CuSe} + \text{InSe} \rightarrow \text{CuInSe}_2$
- $\text{Cu}_2\text{Se} + 2\text{InSe} + \text{Se} \rightarrow 2\text{CuInSe}_2$
- $\text{Cu}_2\text{Se} + \text{In}_2\text{Se}_3 \rightarrow 2\text{CuInSe}_2$

(Herget et. al. J. Phys. Chem. Solids 66 (2005) 1903-1907.) Precursors  $\text{Cu}_{11}\text{In}_9$   $\text{CuIn}_2$   $\text{CuSe}_2$   $\text{In}_4\text{Se}_3$  stacked elemental layers

Kim et al. J.Phys. Chem Solids. 66 (2005) 1915-1919:

$\alpha\text{-CuInSe}_2$  form from an  $\text{In}_2\text{Se}_3/\text{CuSe}$  bilayer precursor film.

Matsushita et al. J. Cryst. Growth 237-239 (2002) 1986-1992.

Chemical reactions occurring to synthesize a single phase

$\text{Cu} + \text{In} + 2\text{In}$

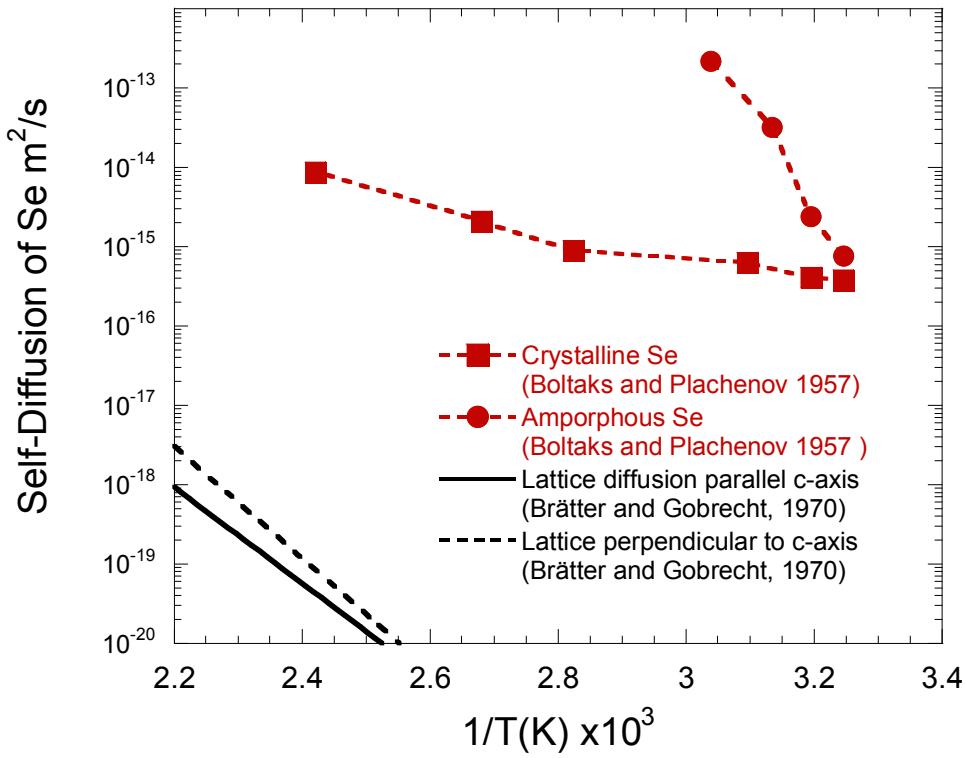
- (1) In, Se  $\rightarrow$   $\text{In}_2\text{Se}$ ,  $\text{In}_6\text{Se}_7$  at 250C
- (2) Cu,Se  $\rightarrow$   $\text{Cu}_3\text{Se}_2$ ,  $\text{Cu}_7\text{Se}_4$  at 280-420C
- (3)  $\text{In}_2\text{Se}$ : solid  $\rightarrow$  liquid at 500C
- (4)  $\text{InSe}$ ,  $\text{In}_6\text{Se}_7$ : solid  $\rightarrow$  liquid at  $\sim 600$  C
- (5)  $\text{In}_2\text{Se}_3$ : solid  $\rightarrow$  liquid at  $\sim 900$  C
- (6)  $\text{Cu}_7\text{Se}_4$ ,  $\text{InSe}$ ,  $\text{In}_2\text{Se}_3 \rightarrow \text{CuInSe}_2$  above 950 C
- (7)  $\text{CuInSe}_2$  (spalerite): solid  $\rightarrow$  liquid at 996 C

# Reactions during Thermal Processing

- $\text{CuIn} + 2\text{Se}$ 
  - $\text{Cu}_{1-x}\text{In}$  ( $x > 0.5$ ),  $\text{Se} \rightarrow \text{CuInSe}_2$ ,  $\text{InSe}$  at 520 C
  - $\text{Cu}_{1-x}\text{In}$  ( $x < 0.5$ ),  $\text{Se InSe} \rightarrow \text{CuInSe}_2$  at 575 C
  - $\text{InSe}$ : solid  $\rightarrow$  liquid at 650 C
  - $\text{CuInSe}_2$ : chalcopyrite  $\rightarrow$  spalerite at about 810 C
  - $\text{CuSe}, \text{InSe} \rightarrow \text{CuInSe}_2$  above 950 C
  - $\text{CuInSe}_2$  (spalerite) : solid  $\rightarrow$  liquid at 996 C.
- W. Kim (J. Crystal Growth, 294 (2006) 231-235
  - $\alpha\text{-CuInSe}_2$  form by selenization by Cu-In precursor
- Other precursors noted  $\text{Cu}_7\text{In}_3$   $\eta\text{-Cu}_{16}\text{In}_9$   $\text{Cu}_{11}\text{In}_9$

# Se Self-Diffusion

Se Crystal Structure: Trigonal (monoclinic)



First experiments by Boltaks and Plachenov 1957

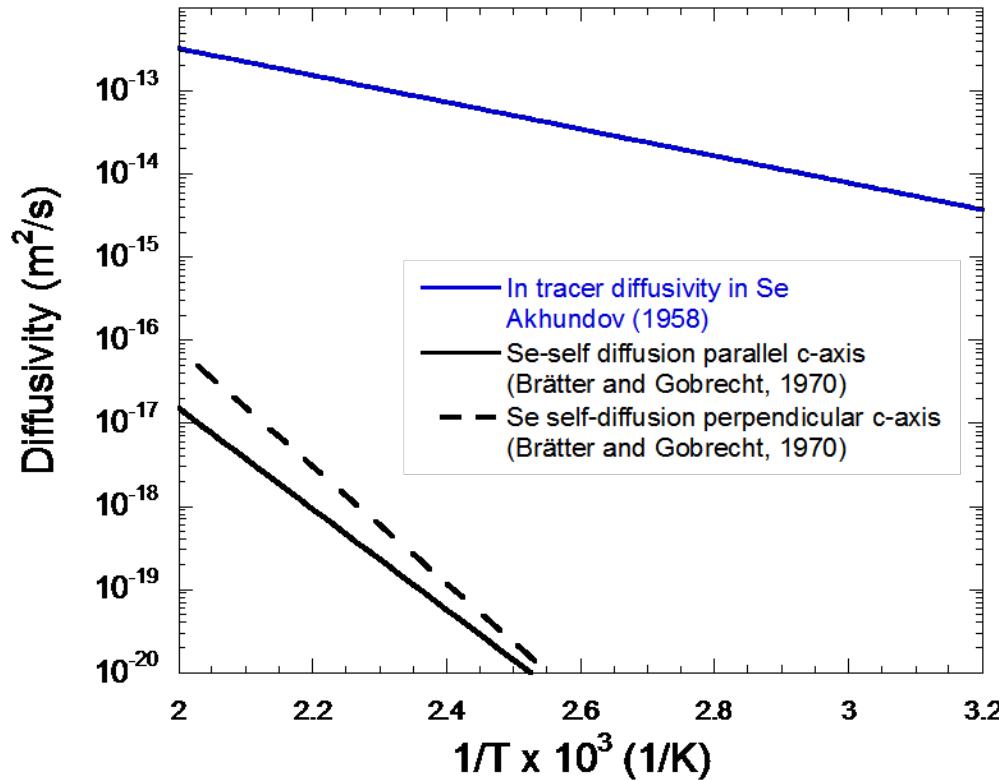
- Used a hexagonal form of Se
- Performed tracer diffusivities experiments with  $\text{Se}^{75}$  using sectioning methods

Brätrer and Gobrecht (1970) measured lattice diffusion and short circuit diffusion for the self diffusion of Se in single crystals

Boltaks and Plachenov most likely measured a short-circuit diffusivity.

# In Diffusion in Se

Akhundov (1958) used In<sup>114</sup> to measure the In diffusion in Se in the 50 °C to 200 ° C temperature range

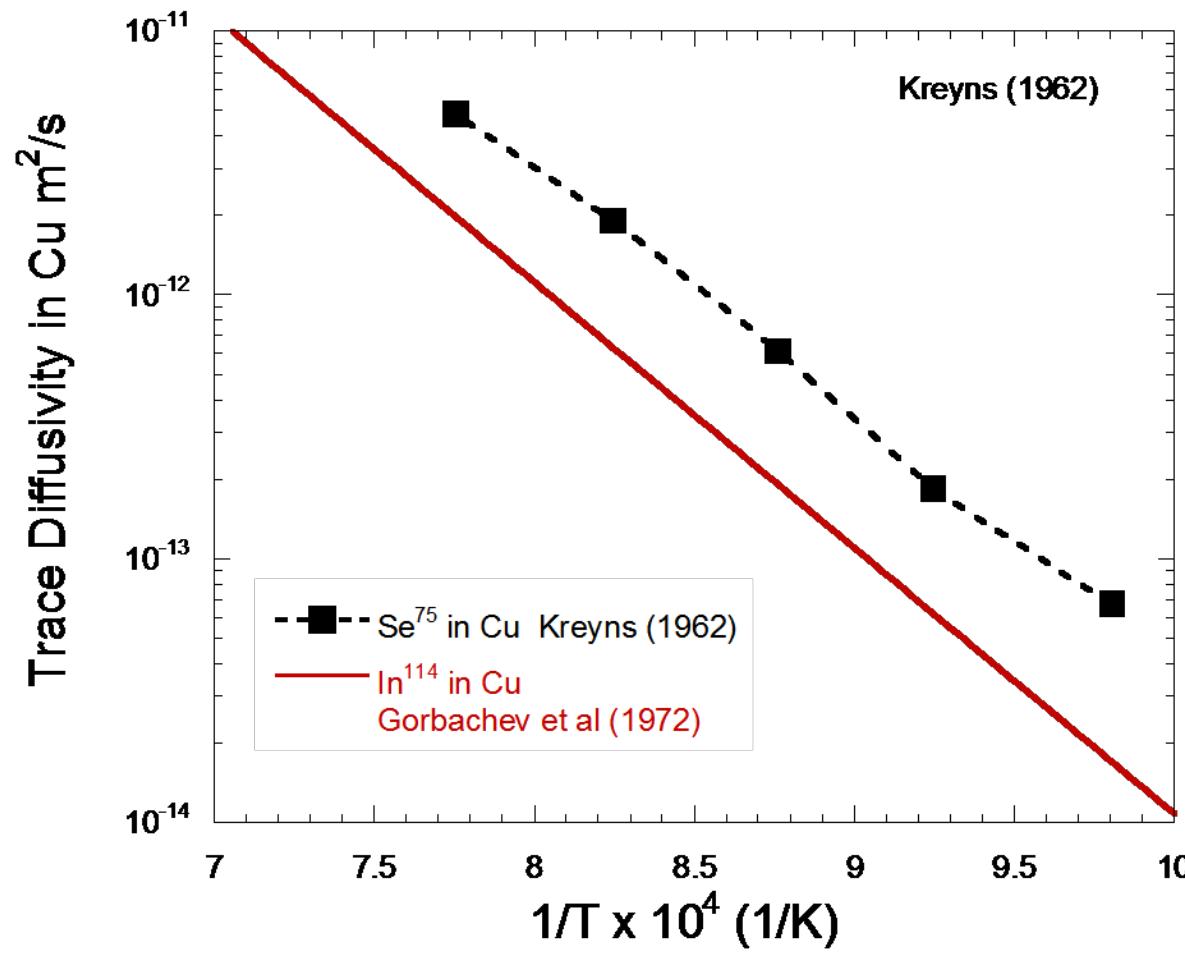


$$D_{In \rightarrow Se} = 5.2 \times 10^{-6} \exp\left(-\frac{31000}{RT}\right) \text{ cm}^2 \cdot \text{s}^{-1}$$

Aknaundov concluded that the low activation energy indicated an interstitial diffusion mechanism. Mostly the measurements are of short-circuit diffusion mechanism (i.e. grain boundary diffusion).



# Diffusion in Cu



Se diffusion in Cu is greater than In in Cu.

$$D_{\text{In} \rightarrow \text{Cu}} = 1.3 \pm 0.15 \exp\left(-\frac{193000}{RT}\right) \text{ cm}^2 \cdot \text{s}^{-1}$$

- V. A. Gorbachev et al. Fiz. Met. Metalloved 34 (1972) 879-83.
- P. H. Kreyns, The Diffusion of Radioactive Tracer  $\text{Se}^{75}$  into Copper Single Crystal, (MS Thesis) U. Arizona, (1962).

# Cu Diffusion in Cu<sub>2</sub>Se

Measured by Hauffe (1955)

$$D_{Cu \rightarrow Cu_2Se} = 3.5 \times 10^{-2} \exp\left(-\frac{29000}{RT}\right) cm^2 s^{-1}$$

Low activation energy indicates some type defect-controlled diffusion mechanism

Maymyko Pavlyuchenko and Pokrovskii (1972) studied Cu diffusion in Cu<sub>2-x</sub>Se between 150 °C and 445° C.

$$D_{Cu \rightarrow Cu_2Se} = 1.3 \begin{array}{l} +0.8 \\ -0.5 \end{array} \times 10^{-4} \exp\left(-\frac{3130 \pm 600}{RT}\right) cm^2 s^{-1}$$

$$D_{Cu \rightarrow Cu_{1.8}Se} = 8.5 \begin{array}{l} +6.3 \\ -3.6 \end{array} \times 10^{-4} \exp\left(-\frac{3960 \pm 600}{RT}\right) cm^2 s^{-1}$$

K. Hauffe, "Reaktionen in und an festen Stoffen." Berlin, 1955.

S. G. Maymyko, M.M. Pavlyuchenko and I.I.Pokrovskii, Dokl. Akad. Nauk.Beloruss. SSR 16 No 6 (1972) 521-3.

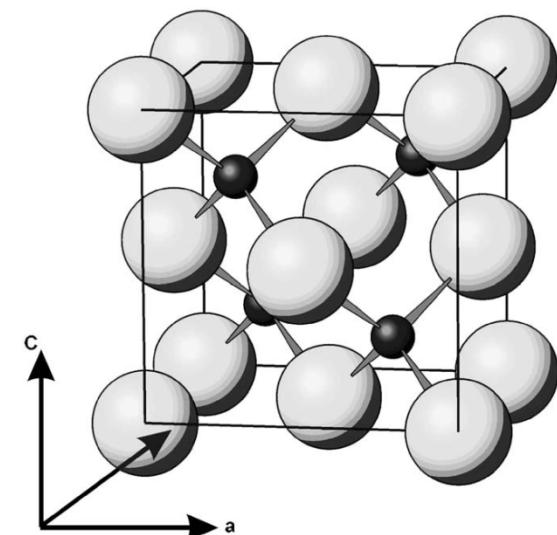


# Diffusion in Cu<sub>2-x</sub>Se (Cu,Va) (Cu,In) Se

Reinhold and Möhring (1937) measured the diffusivity of Cu<sup>+1</sup> ions in Cu<sub>2-x</sub>Se where 0.11 < x < 0.22.

$$D_{Cu^{+1} \rightarrow Cu_{2-x}Se} = 5.6 \times 10^{-4} \text{ cm}^2 \text{s}^{-1} \text{ at } 723 \text{ K}$$

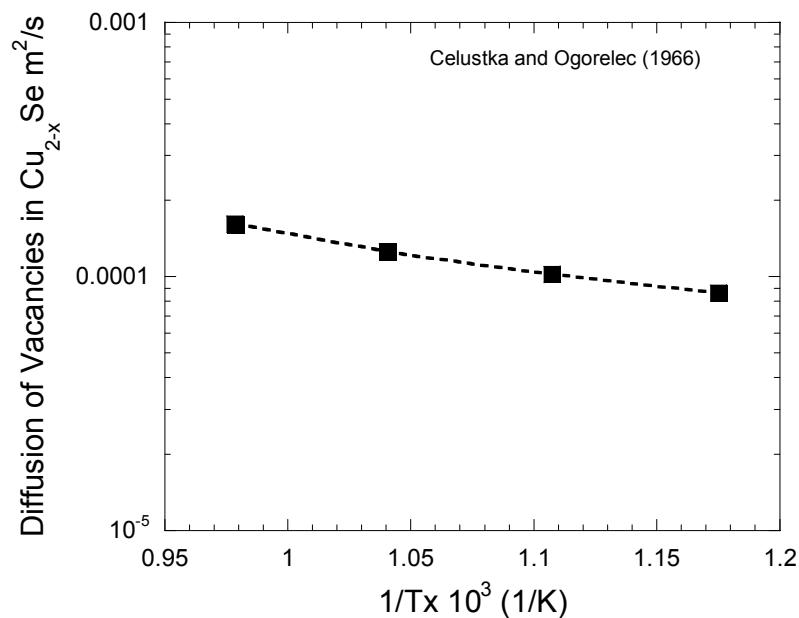
$$D_{Cu^{+1} \rightarrow Cu_{2-x}Se} = 0.2 \times 10^{-4} \text{ cm}^2 \text{s}^{-1} \text{ at } 298 \text{ K}$$



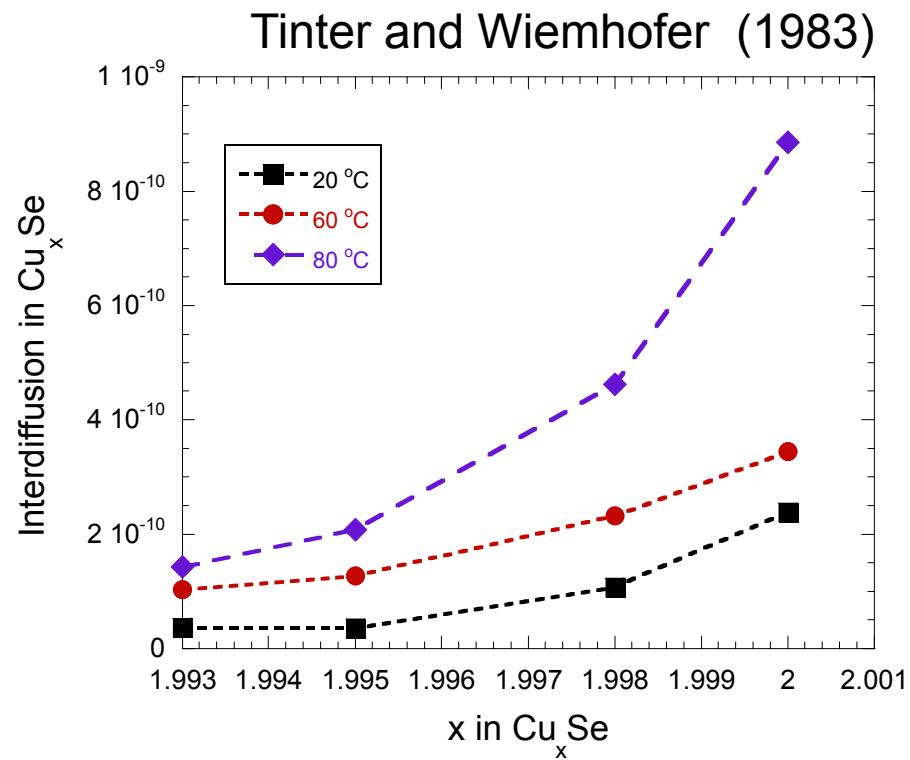
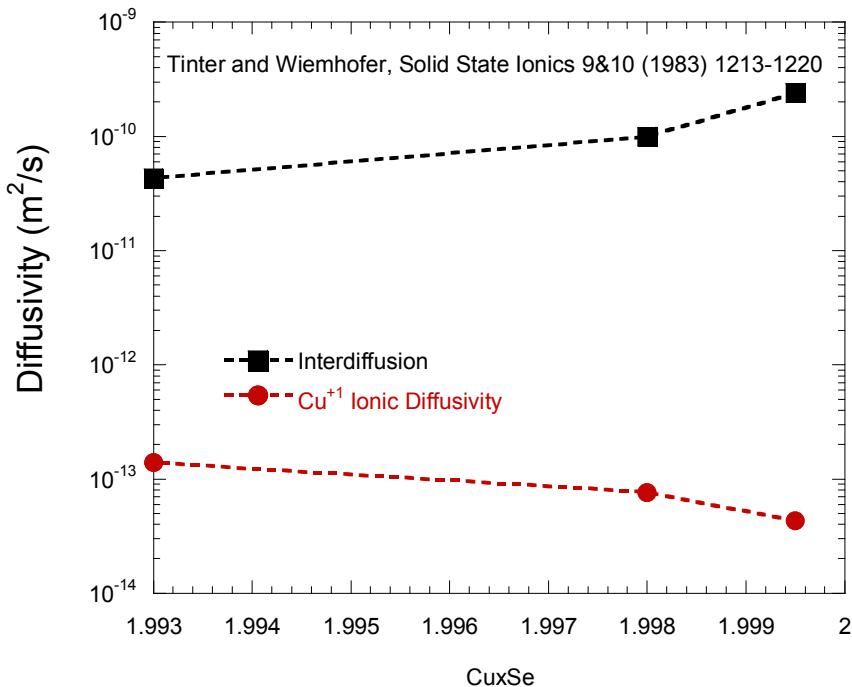
The zincblende sublattice of β-Cu<sub>2</sub>Se.  
The cations and Se<sub>2</sub> anions are each stacked like ABC along the /111S direction. Cu+: dark, Se<sub>2</sub>: bright balls.

Čelustka and Ogorelec measured the diffusion of vacancies in Cu<sub>1.96</sub>Se from 500 °C to 850 °C

$$D_{Va \rightarrow Cu_{2-x}Se} = 0.36 \exp\left(-\frac{34700}{RT}\right) \text{ cm}^2 \text{s}^{-1}$$



# Diffusion in $\text{Cu}_x\text{Se}$

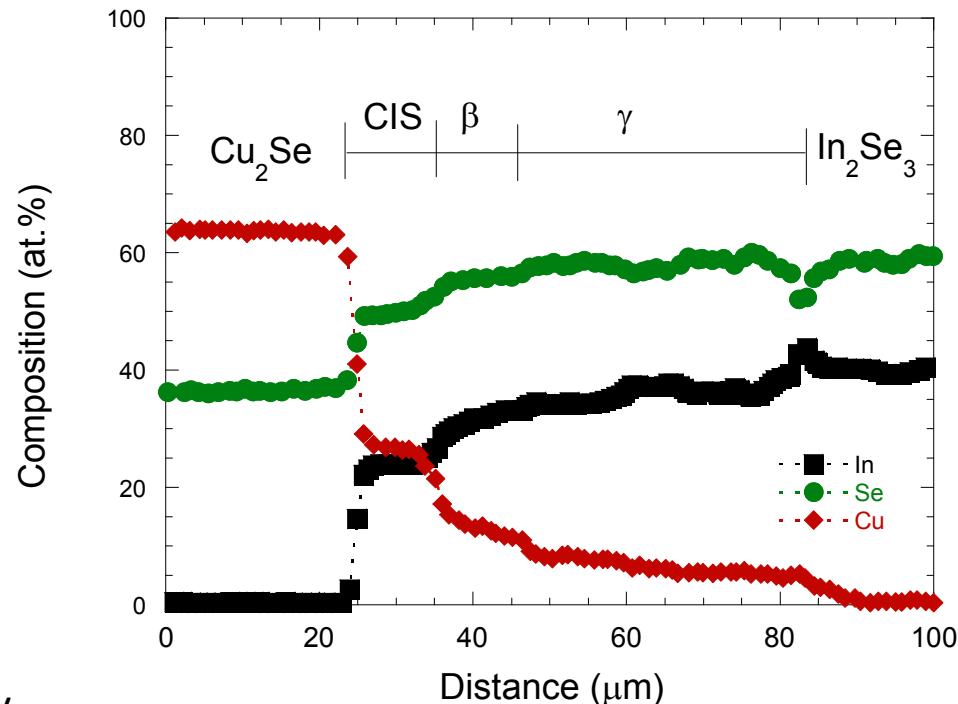
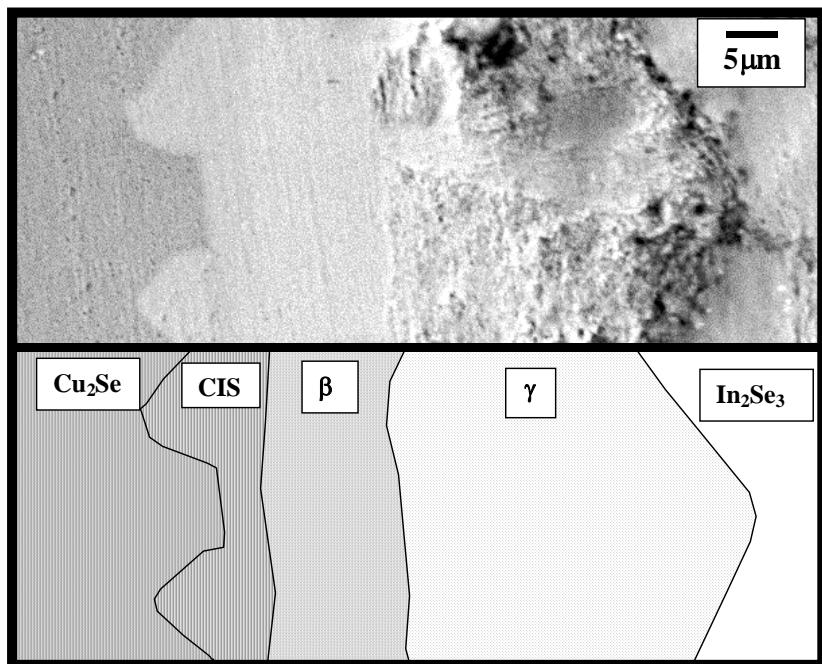


# $\text{Cu}_2\text{Se}/\text{In}_2\text{Se}_3$ Diffusion Couple at 550 °C for 1.5 h

CIS =  $\text{CuInSe}_2$

$\beta$  = defect chalcopyrite ( $\text{CuIn}_3\text{Se}_5$ )

$\gamma$  =  $\text{CuIn}_5\text{Se}_8$



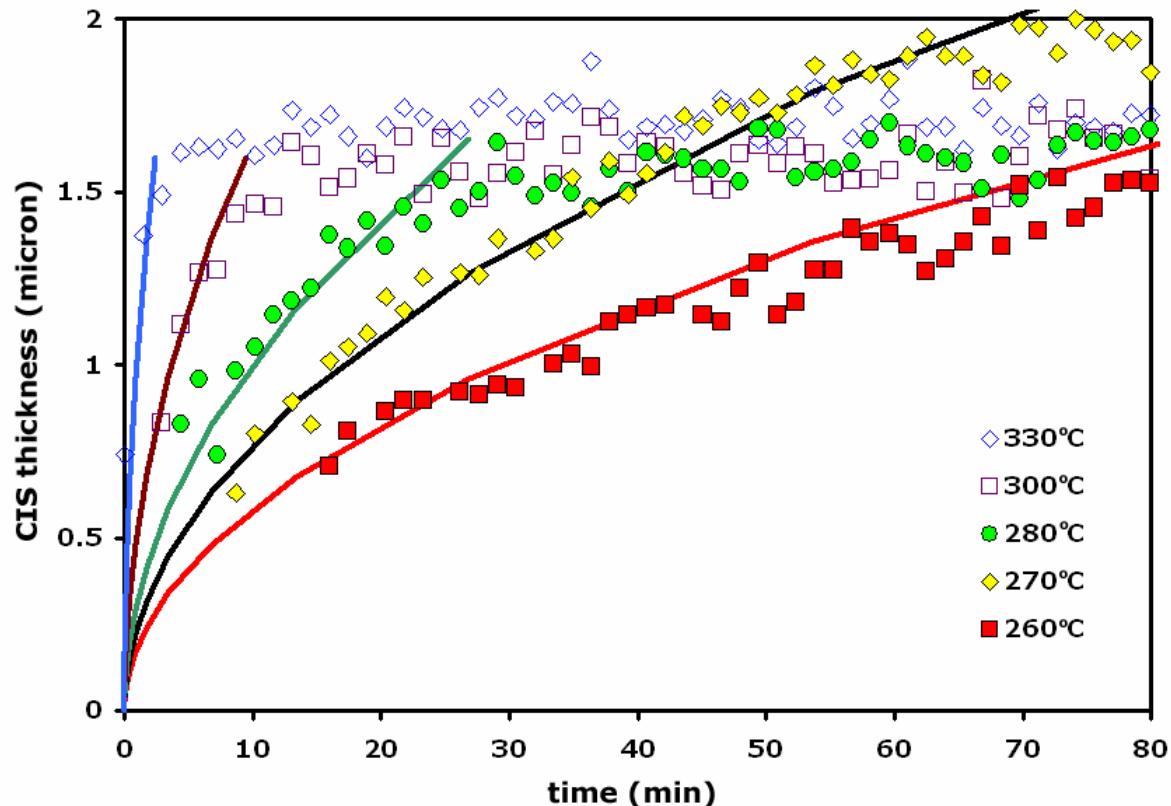
Estimate of In diffusion in  $\text{Cu}_2\text{Se} = 4.2 \times 10^{-10} \text{ m}^2/\text{s}$

Defect structure leads to rapid diffusion.

In diffuses via an ionic lattice diffusion through the Cu vacancy sites on  $\text{Cu}_2\text{Se}$

Park et. al., J. Appl. Phys. 87 (2000) 3683.

# Mobility of Se in CIS



Activation Energy = 146,725 J/mole  
Frequency Factor = 0.01406 m<sup>2</sup>/s

The comparison of CIS growth rates between the DICTRA prediction (solid lines) and experiments (symbols).

# Interdiffusion in CuInSe<sub>2</sub>

Tell and Bridenbaugh measured the interdiffusion in CuInSe<sub>2</sub> by measuring a junction depth as function of time.

$$\tilde{D}_{CuInSe_2} = 5.5 \times 10^{-14} \text{ } m^2 \text{ s}^{-1} \text{ at } 473 \text{ K}$$

$$\tilde{D}_{CuInSe_2} = 1.4 \times 10^{-14} \text{ } m^2 \text{ s}^{-1} \text{ at } 573 \text{ K}$$

Interdiffusion thought to occur either by

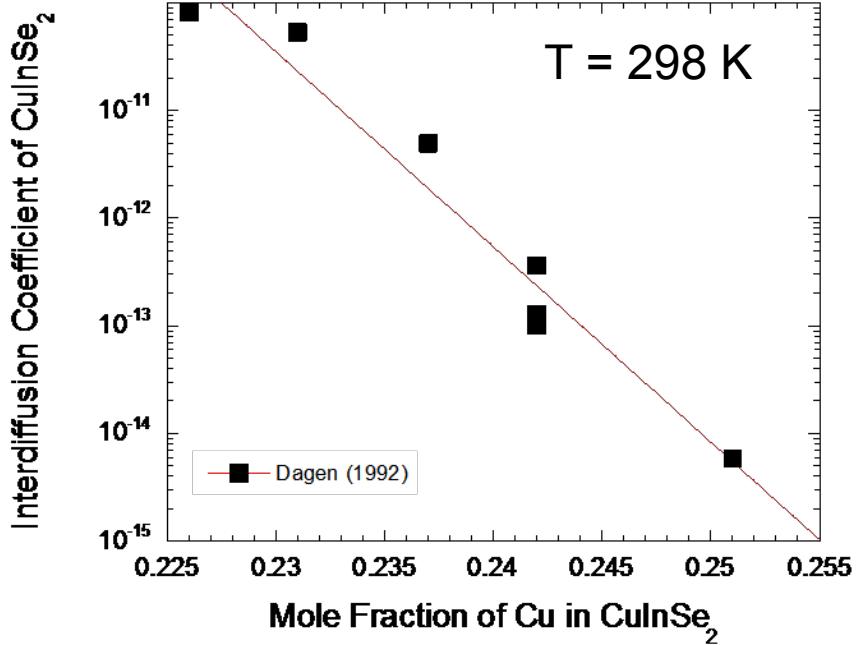
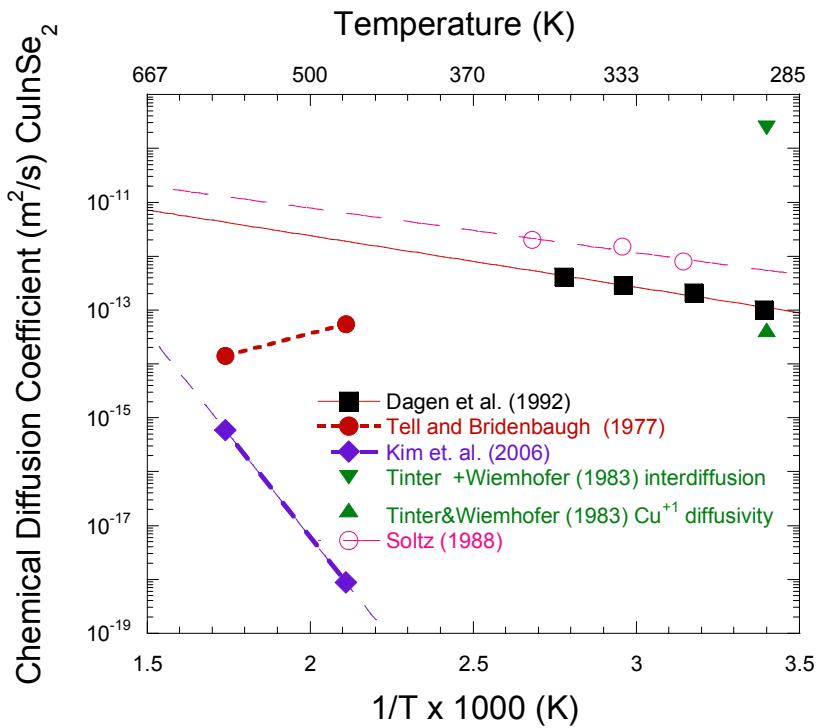
- Se vacancies acting as shallow donors
- Cu interstitials

Compare with Kim's functions

$$D_{Se \rightarrow CuInSe_2} = 8.8 \times 10^{-19} \text{ } m^2 \text{ s}^{-1} \text{ at } 473 \text{ K}$$

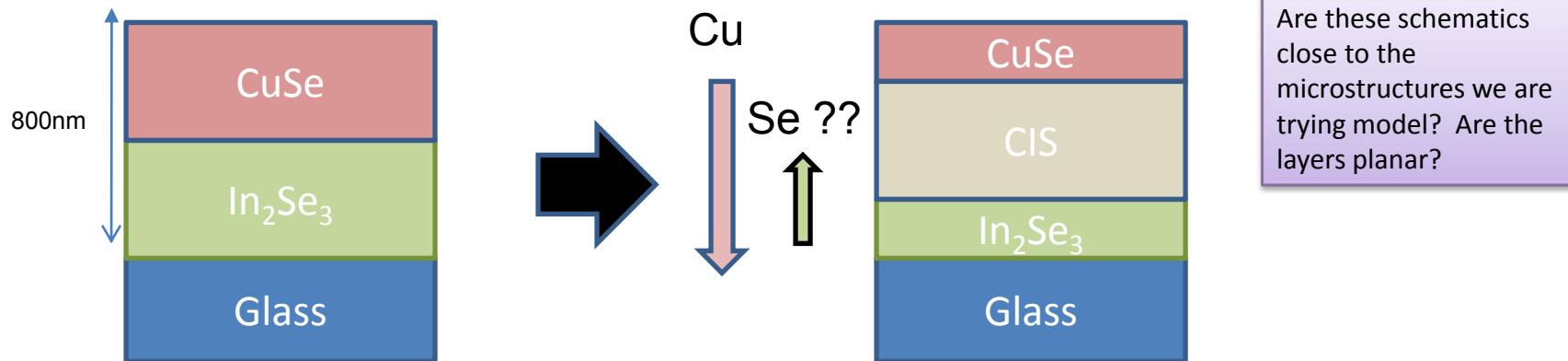
$$D_{Se \rightarrow CuInSe_2} = 5.9 \times 10^{-16} \text{ } m^2 \text{ s}^{-1} \text{ at } 573 \text{ K}$$

# Interdiffusion in CuInSe<sub>2</sub>



# Kim's work

J. Phys. +Chem Solids, 2005. : CuSe/In<sub>2</sub>Se<sub>3</sub> precursor  
• CIS + Se (evaporated)

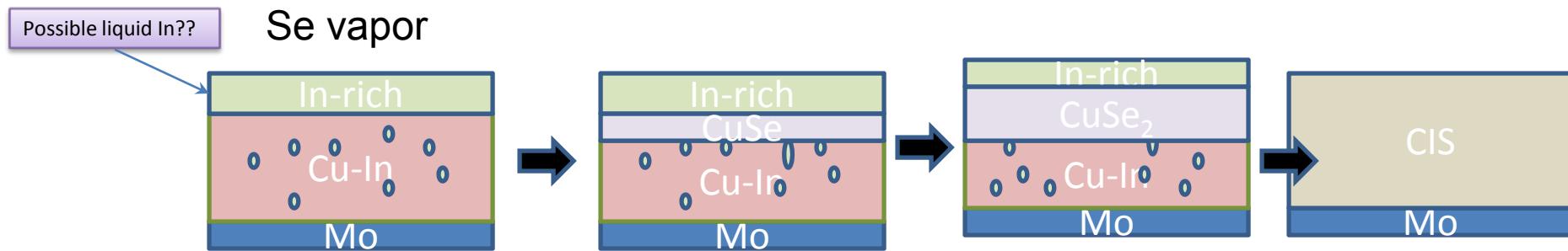


Are these schematics close to the microstructures we are trying model? Are the layers planar?

Activation energy 162 +/- 5 KJ/mol (parabolic model)

J. Crystal Growth , 2005. : Cu/In selenization

- CuSe + In + nSe (vapor)  $\rightarrow$  CuSe<sub>2</sub> + In + nSe (vapor)  $\rightarrow$  CIS



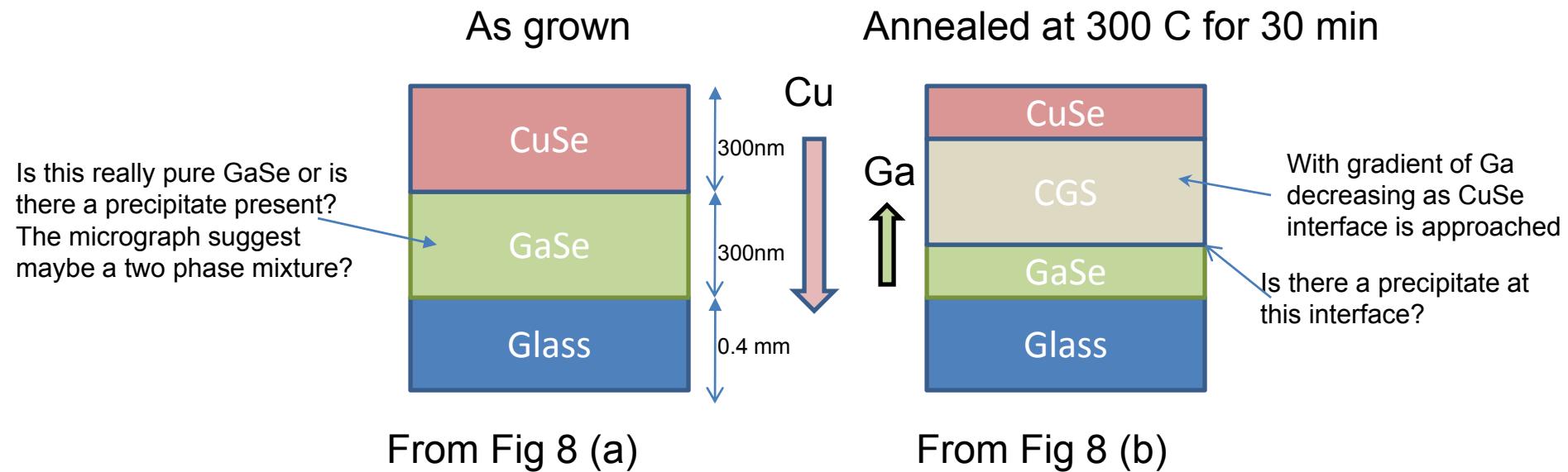
Activation energy 124 +/- 19 kJ/mol (Avrami model); 100 +/- 14 kJ/mol parabolic

# Kim's work

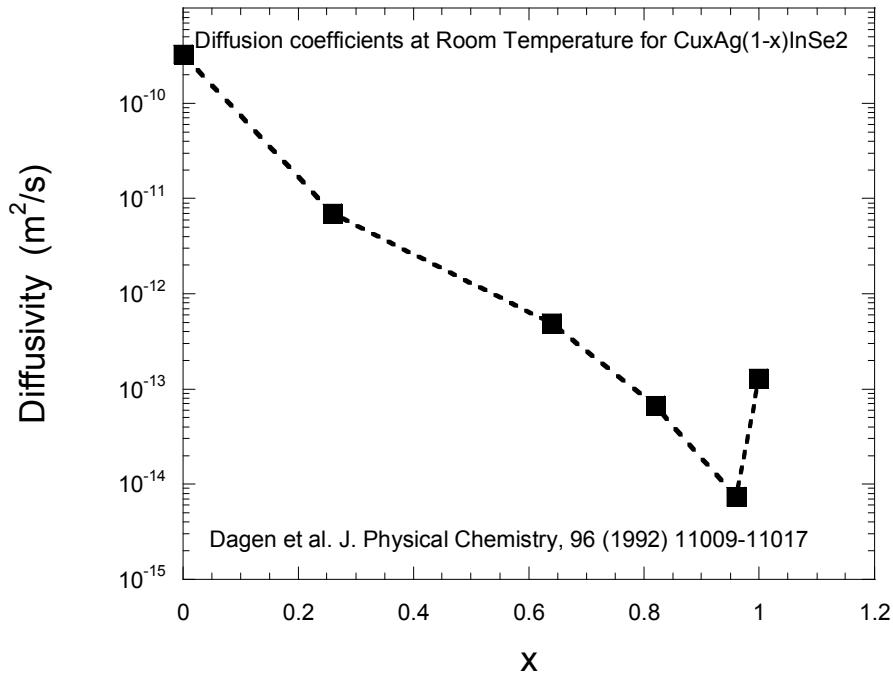
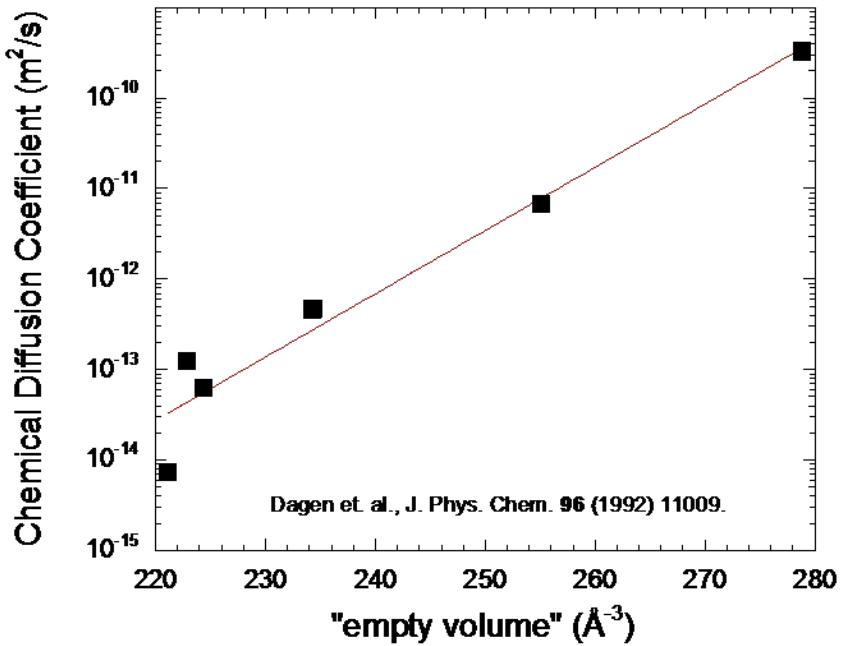
- Summary of reaction pathways and activation energies in J. Crystal Growth 2008, Table 2.

J. Crystal Growth, 2008. : GaSe/CuSe precursor

- $\text{GaSe}(\text{amorph.}) + 1/2\text{Cu}_{2-x}\text{Se} + 1/2\text{Se} \rightarrow \text{CGS}$



# Interdiffusion in $\text{Cu}_x\text{Ag}_{1-x}\text{InSe}_2$



Empty volume per unit cell at room temperature

# Diffusion studies

- Djessas et. al. J. Appl. Phys. 95 (2004) 4111.
  - Studied interdiffusion of Cu, In, Ga diffuse through  $\text{In}_2\text{Se}_3/\text{CuGaSe}_2/\text{SnO}_2$
  - Experimental setup
    - $\text{CuGaSe}_2$  layers grown using close-space vapor transport. Two different grain sizes
    - $\text{In}_2\text{Se}_3$  deposited by thermal evaporation on  $\text{CuGaSe}_2$  at a low substrate temp.
    - Heterostructures annealed at different temperatures
    - Concentration profiles measured using SIMS
  - Results
    - Cu diffuses through  $\text{CuGaSe}_2$  layer to the  $\text{In}_2\text{Se}_3$
    - In diffuses from  $\text{In}_2\text{Se}_3$  through  $\text{CuGaSe}_2$  to  $\text{SnO}_2$
    - Cu diffusion in the  $\text{In}_2\text{Se}_3$  layer is probably grain boundary diffusion
    - Cu and In diffusion away from  $\text{In}_2\text{Se}_3/\text{CuGaSe}_2$  interface mostly likely grain boundary diffusion.

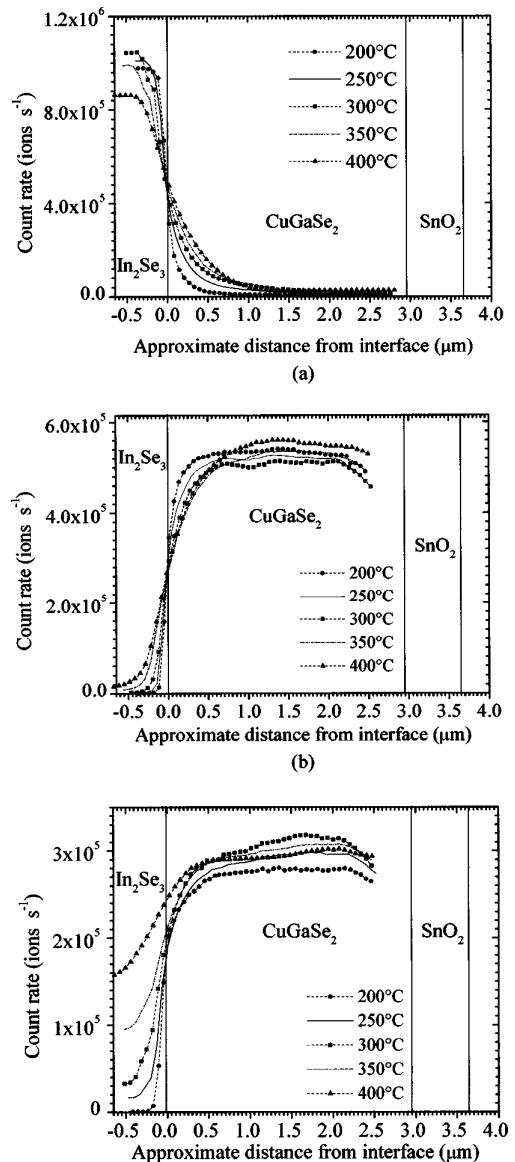
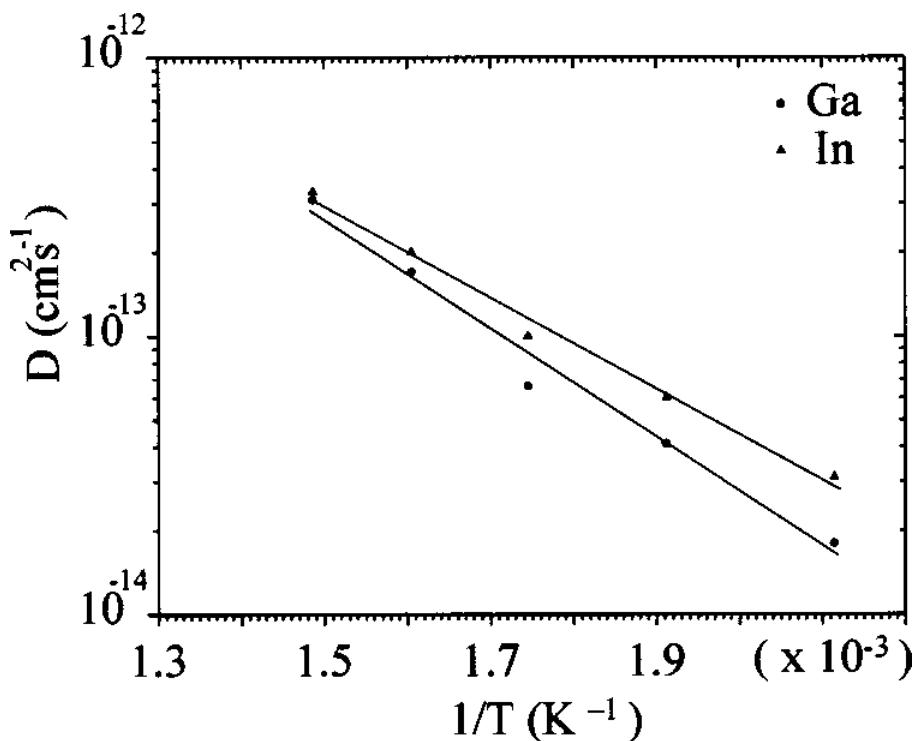


FIG. 1. Indium <sup>a</sup>, gallium <sup>b</sup>, and copper <sup>c</sup>! SIMS concentration profiles in an  $\text{In}_2\text{Se}_3/\text{CuGaSe}_2/\text{SnO}_2$  /glass type I structure annealed in vacuum for 20 min at different temperatures.

# In and Ga diffusion coefficients at a $\text{In}_2\text{Se}_3/\text{CuGaSe}_2$ interface



Indicate possible grain boundary diffusion

FIG. 2. In and Ga diffusion coefficients in terms of the reciprocal temperature.

# Diffusion notes

- J. Djordjevic, J. Crystal. Growth 294 (2006) 218-230.
  - Vapor selenization of Cu layers
    - Cu diffusion coefficient in  $\text{Cu}_{2-x}\text{Se}$  is orders of magnitude higher than Se in  $\text{CuInSe}_4$
    - Rate determining step is surface reaction and not Cu diffusion
  - In selenization
    - Control by In diffusion through layers  $\text{In}_4\text{Se}_3 \rightarrow \text{InSe} \rightarrow \text{In}_2\text{Se}_3$
    - Se incorporated at the surface of the growing film
  - $\text{CuInSe}_2$  from  $\text{Cu}_{x|\text{In}}$  precursors: two reaction paths depending on Cu/In
    - In diffusion into  $\text{Cu}_{2-x}\text{Se}$
    - reaction of InSe and  $\text{Cu}_{2-x}\text{Se}$
- Diffusion data by Lyubormirsky, Dagen and Klenfeld all indicate some dependence on
  - Ionic conductivity (concentration and mobility)
  - p vs n conductor
- Diffusion measurements dependent on type measurement made: (Lyubormirsky et al. 1998) -- need watch out when using published data.
  - Tracer diffusion measurements (concentration gradient)
  - p-n junction methods ( $\sim$  two order of magnitude higher than tracer diffusion)
  - Potentiostatic current decay method (higher than p-n junction) methods

# Diffusion Notes

- F. Herget et. al. (Phys. Stat. Sol. A 203 (2006) 2615.) Chemical solid-state reactions promoted by epitaxy.
  - Need epitaxial relation to exist, for ion diffusion to start.
  - If a redox reaction is energetically favorable, it will occur as a 2<sup>nd</sup> step. (electron exchange must occur first)
  - Ion diffusion is easier if one structure is ion conductive
  - CuSe + GaSe → CuGaSe<sub>2</sub>
    - Assuming the anion sublattices of all 3 compounds are equal, then only have cations redistribute via interdiffusion.
    - Cation radii << anion radii, so diffusion is relative fast.
    - $\frac{1}{2}\beta\text{-Cu}_2\text{Se} + \text{InSe} + \frac{1}{2}\text{Se(liq)} \rightarrow \text{CuInSe}_2$  Reaction C (SEL) of (Hergert et al. J. Solid State Chem. 179 (2006) 2394.)
      - Driven by In<sup>+3</sup> diffusion

# How to Proceed??

- Diffusion in solid solutions ✓
- Diffusion in stoichiometric phases: binaries ok, but need data
- Diffusion in ternary compound phases
  - $\alpha$  CuInSe<sub>2</sub> (Cu%,In,Va)(Cu,In%,Va)Se<sub>2</sub> (Chalcopyrite)  
????
  - Are the current thermodynamics adequate to deal with the diffusion accurately?? Some question about needing to treat the charged species?